Unit in mm

TOSHIBA GTR MODULE SILICON N CHANNEL IGBT

MG150Q2YS50

HIGH POWER SWITCHING APPLICATIONS

MOTOR CONTROL APPLICATIONS

• High Input Impedance

• High Speed : $t_f = 0.3 \mu s$ (Max.)

@Inductive Load

• Low Saturation Voltage

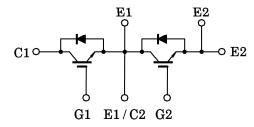
: $V_{CE (sat)} = 3.6V (Max.)$

• Enhancement-Mode

• Includes a Complete Half Bridge in One Package.

• The Electrodes are Isolated from Case.

EQUIVALENT CIRCUIT



MAXIMUM RATINGS (Ta = 25°C)

4-FAST-ON-TAB#110 2-Ø5.4±0.3 3-M5 90 01 01 01 01 01 01 01 01 01 0
80 ± 0.3 94 ^{+0.6}
7±0.5 7±0.5 16±0.5 16±0.5 16±0.5 14 20±0.5 10±0.5 16±0.5 1
91.6 ± 0.5 45.7 ± 0.5
JEDEC —
EIAJ —
TOSHIBA 2-95A4A

Weight: 255g

MAXIMON NATINGS (14 = 2:	,				
CHARACTERISTIC	SYMBOL	RATING	UNIT		
Collector-Emitter Voltage	v_{CES}	1200	V		
Gate-Emitter Voltage	v_{GES}	±20	V		
Collector Current	DC	I _C (25°C / 80°C)	200 / 150	A	
Conector Current	1ms	I _{CP} (25°C / 80°C)	400/300	A	
Forward Current	DC	$I_{\mathbf{F}}$	150	A	
rorward Current	1ms	I_{FM}	300		
Collector Power Dissipation (Tc=25°C)	PC	1250	W		
Junction Temperature	T_{j}	150	°C		
Storage Temperature Ran	$\mathrm{T_{stg}}$	-40~125	$^{\circ}\mathrm{C}$		
Isolation Voltage	V _{Isol} 2500 (AC 1 minute)		V		
Screw Torque (Terminal / Mounting)		_	3/3	N∙m	

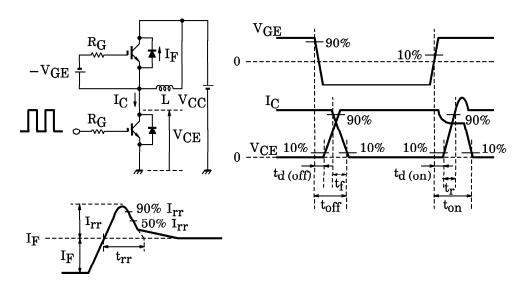
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ELECTRICAL C	CHARACTERISTICS	$(Ta = 25^{\circ}C)$
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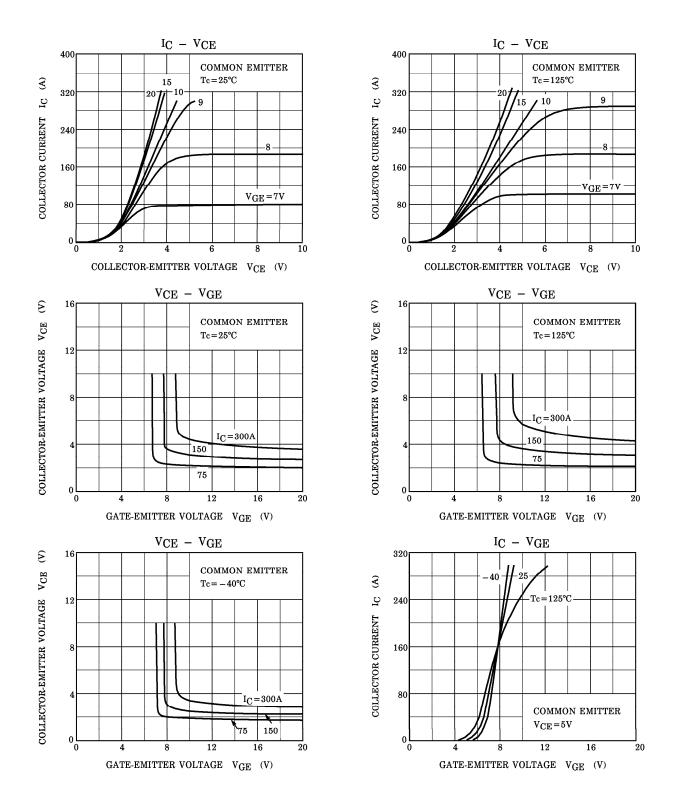
СНА	RACTERISTIC	SYMBOL	TEST CONDIT	ION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		$I_{ ext{GES}}$	$V_{GE} = \pm 20V, V_{CE} = 0$		_	_	±500	nA
Collector Cut-off Current		ICES	$V_{CE} = 1200V, V_{GE} = 0$			_	2.0	mA
Gate-Emitter Cut-off Voltage		V _{GE (off)}	$I_{C}=150 \text{mA}, V_{CE}=5 \text{V}$		3.0	_	6.0	V
Collector-Emitter Saturation Voltage		V _{CE} (sat)	I _C =150A,	$T_j = 25$ °C	_	2.8	3.6	⊣ V
				$T_j = 125$ °C	1	3.1	4.0	
Input Cap	acitance	$\mathrm{C_{ies}}$	$V_{CE} = 10V, V_{GE} = 0, f = 1MHz$		l	18.0		nF
Switching Time	Turn-on Delay Time	t _{d (on)}	Inductive Load		1	0.05	_	
	Rise Time	t_r	V _{CC} =600V		l	0.05	_	μs
	Turn-on Time	t_{on}	$I_{C}=150A$ $V_{GE}=\pm 15V$ $R_{G}=5.6\Omega$			0.2	_	
	Turn-off Delay Time	t _{d (off)}				0.5	_	
	Fall Time	t_f		(Note 1)		0.1	0.3	
	Turn-off Time	$t_{ ext{off}}$			_	0.6	_	
Forward V	oltage o	$ m V_{f F}$	$I_{F} = 150A, V_{GE} = 0$		_	2.4	3.5	V
Reverse Recovery Time		t _{rr}	$I_F = 150A$, $V_{GE} = -1$ di / dt = $700A$ / μ s	.0V (Note 1)		0.1	0.25	/18
Thermal Resistance		R _{th (j-c)}	Transistor Stage			_	0.1	°C/W
			Diode Stage		_	_	0.32	O / W

Note 1: Switching Time and Reverse Recovery Time Test Circuit & Timing Chart



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GATE-EMITTER VOLTAGE VGE

